


<b>Chemical analysis and imaging of elements implanted in metallic alloys for nuclear applications</b>	
	
<b>Laboratory / Team</b>	Center for Nuclear Sciences and Material Sciences (CSNSM) Materials and Irradiation team <a href="https://www.csnsm.in2p3.fr/Materiaux-et-Irradiation">https://www.csnsm.in2p3.fr/Materiaux-et-Irradiation</a>
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<b>Main topics</b>	Materials synthesis by ion implantation, characterization by transmission electron microscopy (TEM, STEM) and related analytical techniques (EDX, ...), Calibration and optimization of the new EDX detector (@ JANNuS-Orsay)
<b>Objectives/context</b>	Calibrate and optimize the new EDX detector, to determine the spatial distribution and quantity of an element introduced by ion implantation in metallic alloys for nuclear applications (e.g. ODS steel)
<b>Equipment / tools / software used</b>	Tools for preparation of thin foils for TEM; transmission electron microscope (TEM) and ion accelerators (JANNuS-Orsay) and analytical techniques (EDX, ...); SRIM, Digital Micrograph, ESPRIT2.1 Brucker softwares
<b>Level / Duration / Period</b>	Master 1 / 1 to 3 months / April-July 2019
<b>Number of trainees</b>	Only one student
<b>Course description / main tasks</b>	
<ul style="list-style-type: none"> <li>• Determination of the experimental conditions needed for ion implantation in thin foils of a high purity metallic alloy: use of SRIM simulation code.</li> <li>• Calibration of the new EDX detector using reference specimens.</li> <li>• Measurement in the transmission electron microscope of the EDX spectra (Energy-Dispersive X-ray Spectroscopy) of the implanted material, and acquisition of corresponding images.</li> <li>• Analysis of images and EDX spectra obtained: use of Digital Micrograph and ESPRIT Brucker softwares. Obtaining quantity and spatial distribution of elements implanted in the matrix.</li> <li>• Update the procedure for EDX experiments (in TEM and STEM modes)</li> </ul>	
<b>Skills acquired on completion of the course</b>	
<ul style="list-style-type: none"> <li>• Estimation of the range of charged particles in a material - use of a SRIM Monte-Carlo simulation code; principle of an ion implanter.</li> <li>• Knowledge of vacuum, ion accelerator and transmission electron microscopy techniques.</li> <li>• Principle of Energy-Dispersive X-ray Spectroscopy to determine spatial distribution and quantity of elements contained in a metallic alloy, and its calibration.</li> <li>• Acquisition and analysis of images and EDX spectra: determination of the type of implanted elements, extraction of spatial distribution and quantity of elements implanted in the alloy.</li> <li>• Writing a procedure for the users</li> </ul>	